



G00002

A B S T R A C T

Array substrates are prepared, each of which includes a substrate on which a plurality of scanning lines and a plurality of signal lines are disposed to intersect each other, pixel portions, which are formed on the substrate, arranged close to intersections of the scanning lines and the signal lines and includes switching elements and auxiliary capacitors, and a plurality of inspection pad array that is connected to the scanning lines and signal lines and are arranged in accordance with the arrangement of probes of an inspection apparatus. The probes are connected to the inspection pad arrays, and charges are accumulated in auxiliary capacitor of each pixel portion, following which the condition of the array substrates is inspected.